Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,112	KIM, JIN HYUN	
Examiner	Art Unit	
Shortall Partic	2617	

SEARCHED			
Class	Subclass	Date	Examiner
370	352,400, 338,237, 228	11/20/2006	SLP
370	401,410	11/20/2006	SLP
370	465,469	11/20/2006	SLP
709		11/20/2006	SLP

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARC (INCLUDING SE	H NOTE	S TRATEGY	)
		DATE	EXMR
See Attached		11/20/2006	SLP
No Updates		5/16/2007	SLP
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